

**Search Notes**

Application/Control No.

10/622,116

Examiner

Thomas D. Lee

Applicant(s)/Patent under  
Reexamination

MEIER ET AL.

Art Unit

2625

**SEARCHED**

Class	Subclass	Date	Examiner
382	162, 176	4/26/2007	TDL
358	504, 518	4/26/2007	TDL
358	520	4/26/2007	TDL
updated		12/10/2007	TDL
358	1.9	12/10/2007	TDL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Interference Search Printout		12/10/2007	TDL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Search History Printout	4/26/2007	TDL